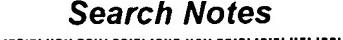


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/082,081	LEE, CHULHEE
	Examiner	Art Unit
	Dave Czekaj	2613

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner